TOSHIBA Photocoupler IRED & Photo IC

TLP551

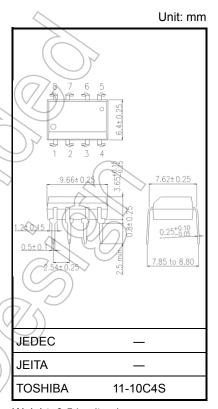
Controllers

Interfaces for Calculators and Control Devices
Noise Attenuation in Measurement and System Devices
Signal Transmission between circuits of different potential

The TOSHIBA TLP551 consists of a high-output infrared emitting diode and a high speed detector of one chip photo diode-transistor. This unit is 8-lead DIP.

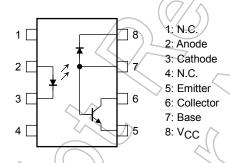
TLP551 has an internal base connection. This base pin should be used for analog application or enable operation.

- Isolation voltage: 2500 V_{rms} (min)
- Switching speed: t_{pHL} = 0.5 μs (typ.) t_{pLH} = 0.6 μs (typ.) $(R_L$ = 1.9 $k\Omega)$
- TTL compatible
- If the base pin is open, external noise will cause interference to the output signal. In this scenario, TLP550 will be recommended.
- UL-recognized: UL 1577, File No.E67349
- cUL-recognized: CSA Component Acceptance Service No.5A File No.E67349

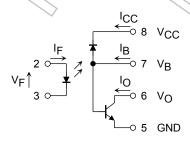


Weight: 0.54 g (typ.)

Pin Configurations (top view)



Schematic



Start of commercial production 1981-09

Absolute Maximum Ratings (Ta = 25°C)

	Characteristics	Symbol	Rating	Unit	
	Forward current	ΙF	25	mA	
	Forward current derating (Ta≥ 70 °C)	ΔIF/ΔTa	-0.8	mA/°C	
	Pulse forward current (Note 1)	I _{FP}	50	mA	
ED	Pulse forward current derating (Ta≥ 70 °C)	ΔIFP/ΔTa	-1.6	mA/°C	
"	Peak transient forward current (Note 2)	IFPT	1	Α	
	Reverse voltage	V _R	5	(V)	
	Diode power dissipation	PD	45	mW	
	Diode power dissipation derating (Ta ≥ 70 °C)	ΔP _D /ΔTa	-0.9	mW/°C	
	Output current	IO	8	mA	
	Peak output current	IOP	16	mA	
	Output voltage	VO	−0.5 to 15	V	
ctor	Supply voltage	V _{CC}	-0.5 to 15	V	
Detector	Base current	IB	(5)	mA	
	Emitter-base reverse voltage	VEB	5	٧	
	Output power dissipation	Po	100	mW	
	Output power dissipation derating (Ta≥ 70 °C)	ΔΡ ₀ /ΔΤα	-1.8	mW/°C	
Operating temperature range		Topr	−55 to 100	(/c	
Storage temperature range		T _{stg}	-55 to 125	(e)	
Lead solder temperature (10 s) (Note 3)		T _{SOI}	260	°C	
Isol	ation voltage (AC, 60 s, R.H. ≤ 60 %) (Note 4)	BVS	2500	V _{rms}	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

- Note 1: 50 % duty cycle, 1 µs pulse width.
- Note 2: Pulse width \leq 1 μ s, 300 pps.
- Note 3: Soldering portion of lead: up to 2 mm from body of the device.
- Note 4: Device considered a two-terminal device: Pins 1, 2, 3 and 4 shorted together and pins 5, 6, 7 and 8 shorted together.

Electrical Characteristics (Ta = 25°C)

	Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
	Forward voltage	V_{F}	I _F = 16 mA	1.45	1.65	1.85	V
CED	Forward voltage temperature coefficient	ΔV _F /ΔTa	I _F = 16 mA	_	-2	_	mV/°C
	Reverse current	I _R	V _R = 5 V		_	10	μА
	Capacitance between terminal	C _T	V _F = 0 V, f = 1 MHz	((-)	60	_	pF
Detector		IOH(1)	$I_F = 0 \text{ mA}, V_{CC} = V_O = 5.5 \text{ V}$		3	500	nA
	High level output current	I _{OH(2)}	$I_F = 0 \text{ mA}, V_{CC} = V_O = 15 \text{ W}$	/ }	-	5	μА
	The state of the s	IOH	$I_F = 0 \text{ mA}, V_{CC} = V_O = 15 \text{ V},$ Ta = 70 °C	<u>)</u>		50	μА
	High level supply voltage	ICCH	I _F = 0 mA, V _{CC} = 15 V	1	0.01	1	μА

Coupled Electrical Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
		$I_F = 16 \text{ mA}, V_{CC} = 4.5 \text{ V}, V_O = 0.4 \text{ V}$	70	30	-	- %
Current transfer ratio	lo/le	Rank: O	19	30	-	
Current transfer ratio	IO/IF	$I_F = 16 \text{ mA}, V_{CC} = 4.5 \text{ V}, V_O = 0.4 \text{ V}$	<u></u>	_	_	70
		Ta = 0 to 70°C Rank: O	15	-	-	
Low level output voltage	VOL	$I_F = 16$ mA, $V_{CC} = 4.5$ V, $I_O = 1.1$ mA (Rank O: $I_O = 2.4$ mA)	-	ı	0.4	V

Isolation Characteristics (Ta = 25°C)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Capacitance (input-output)	//cs	$V_S = 0 V, f = 1 MHz$	_	0.8	-	pF
Resistance (input-output)	Rs	$V_S = 500 V_{DC}$, R.H. $\leq 60 \%$ (Note 1)	5 × 10 ¹⁰	10 ¹⁴		Ω
Isolation voltage	BVS	AC, 60 s	2500	ı	_	V _{rms}

Note 1: Device considered a two-terminal device: Pins 1, 2, 3 and 4 shorted together and pins 5, 6, 7 and 8 shorted together.

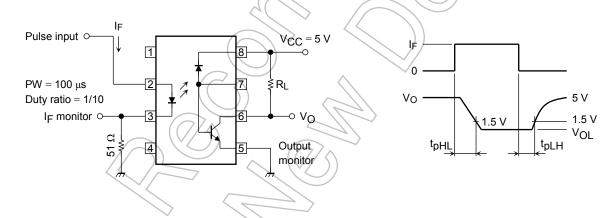
Switching Characteristics (Ta = 25°C, V_{CC} = 5 V)

Characteristics	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
			I_F = 16 mA, R_L = 4.1 kΩ	_	0.3	0.8	
Propagation delay time (H → L)	^t pHL	1	I_F = 16 mA, R_L = 1.9 kΩ (Rank O)	ı	0.5	0.8	μS
			I_F = 16 mA, R_L = 4.1 kΩ		1	2	
Propagation delay time (L → H)	t _{pLH}	1	I_F = 16 mA, R_L = 1.9 kΩ (Rank O)		0.6	1.2	μS
Common mode transient immunity at logic high output	СМН	2	$I_F = 0 \text{ mA}, V_{CM} = 200 V_{p-p}$ $R_L = 4.1 \text{ k}\Omega$ (Rank O: $R_L = 1.9 \text{ k}\Omega$)		400	l	V/μs
Common mode transient immunity at logic low output	CML	2	$\begin{aligned} & \text{I}_{\text{F}} = 16 \text{ mA, V}_{\text{CM}} = 200 \text{ V}_{\text{p-p}} \\ & \text{R}_{\text{L}} = 4.1 \text{ k}\Omega \\ & \text{(Rank O: R}_{\text{L}} = 1.9 \text{ k}\Omega) \end{aligned}$	_	-1000		V/μs

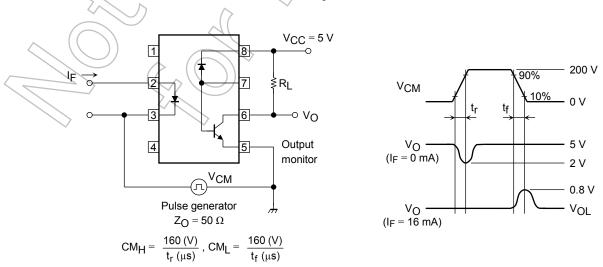
Note: CM_H: The maximum tolerable rate of rise of the common mode voltage to ensure that the output will remain in the high output state (i.e., $V_O > 2.0 \text{ V}$). Measured in volts per microsecond (V/µs).

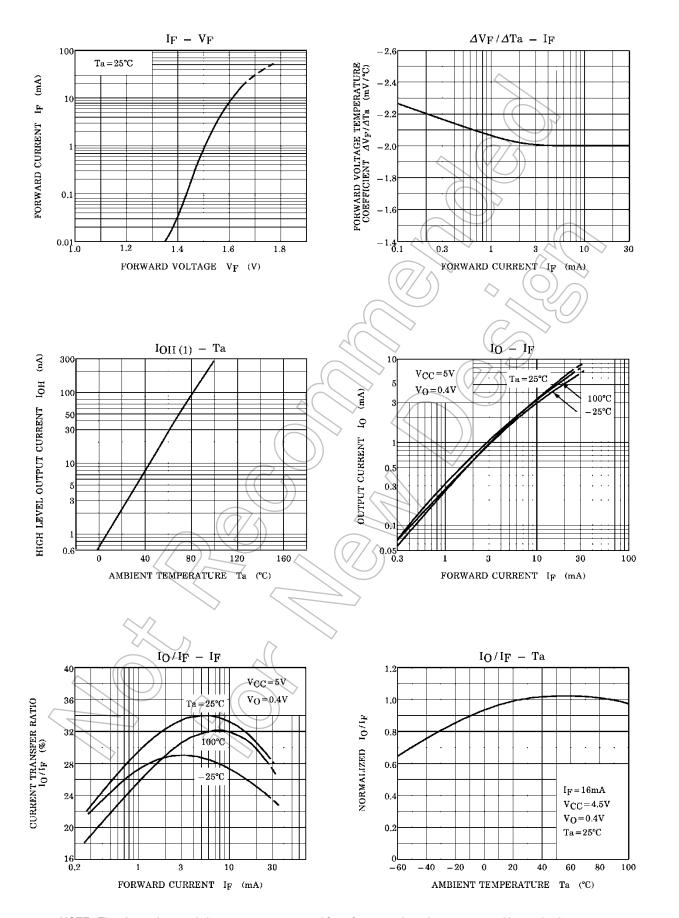
CML: The maximum tolerable rate of fall of the common mode voltage to ensure that the output will remain in the low output state (i.e., $V_O < 0.8 \text{ V}$). Measured in volts per microsecond (V/ μ s).

Test Circuit 1: Switching Time Test Circuit

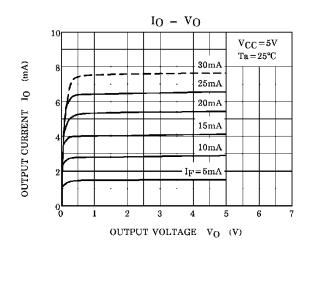


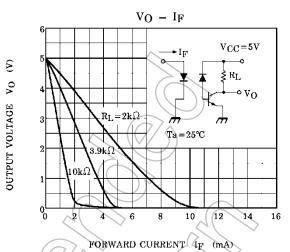
Test Circuit 2: Common Mode Noise Immunity Test Circuit

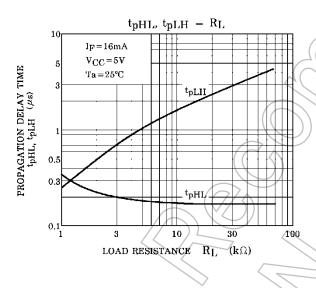




NOTE: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.







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